

## ASIC DESIGN

<b>Course Code</b>	19EC4602C	<b>Year</b>	III	<b>Semester</b>	II
<b>Course Category</b>	Program Elective-III	<b>Branch</b>	ECE	<b>Course Type</b>	Theory
<b>Credits</b>	3	<b>L-T-P</b>	3-0-0	<b>Prerequisites</b>	Digital Logic Design
<b>Continuous Internal Evaluation:</b>	30	<b>Semester End Evaluation:</b>	70	<b>Total Marks:</b>	100

## Course Outcomes

Upon successful completion of the course, the student will be able to	
<b>CO1</b>	Describe the programming technologies of an ASIC and its construction (L2).
<b>CO2</b>	Design and simulation of digital ICs using Verilog (L5)
<b>CO3</b>	Compare different testing procedures for VLSI circuits. (L2)
<b>CO4</b>	Analyze the algorithms of partitioning, placement and routing (L4)

## Mapping of course outcomes with Program outcomes (CO/ PO/PSO Matrix)

Note: 1- Weak correlation 2-Medium correlation 3-Strong correlation

\* - Average value indicates course correlation strength with mapped PO

COs	PO1	PO2	PO3	PO4	PO5	PO6	PO7	PO8	PO9	PO10	PO11	PO12	PSO1	PSO2
CO1	3		3		3					3			3	
CO2	3		3		3					3			3	
CO3	3	3								3			3	
CO4	3	3								3			3	
<b>Average* (Rounded to nearest integer)</b>	3	3	3	3	3					3			3	

## Syllabus

Unit No.	Contents	Mapped CO
I	<b>Types of ASICs:</b> Full-Custom ASICs, Standard-cell-based ASICs, Gate array-based ASICs, channelled gate array, channel less gate array, structured gate array, programmable logic devices, field programmable gate arrays, design flow, case study. ASIC Cell Libraries. ASIC library design: transistors as resistors, transistor parasitic capacitance	CO1
II	<b>Verilog:</b> Basics of the Verilog language, operators, hierarchy, procedures and assignments, timing controls and delay, logic-gate modeling, modelling delay, altering parameters. <b>Logic Synthesis:</b> A logic-synthesis example, MULTIPLEXER, inside a logic synthesizer verilog and logic synthesis.	CO2
III	<b>Simulation:</b> Types of simulation, MUX example, logic systems, how logic simulation works, delay models, static timing analysis, switch-level simulation, transistor-level simulation.	CO2

IV	<b>Test:</b> The importance of test, boundary-scan test, faults, fault simulation, automatic test-pattern generation, scan test, built-in self-test, a simple test example.	CO3
V	<b>ASIC Construction:</b> Physical design, system partitioning, partitioning methods. <b>Floor planning and Placement:</b> Floor planning, placement, physical design flow, <b>Routing:</b> Global routing, detailed routing,	CO4

### Learning Resources

#### Text Books

1. Michael John Sebastian Smith, Application-Specific Integrated Circuits, Pearson Education, 2001.

#### Reference Books

1. Jan. M. Rabaey, Digital Integrated Circuits, 2/e, Prentice Hall, 2001
2. Sabih Gerez, Algorithms for VLSI Design Automation, Wiley, 1999.
3. Wayne Wolf, Modern VLSI Design, 4/e, Pearson Education, 2002.
4. Samir Palnitkar, Verilog HDL, 2/e, Pearson Education, 2003